EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4	fritt$3 and voltage and 324/757.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:48
L2	2	fritt$3 and voltage and 324/756.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:45
L3	4	fritt$3 and voltage and 324/754.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:45
L4	1	fritt$3 and voltage and 324/761.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:45
L5	2	fritt$3 and voltage and 324/765.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:45
L6	5	oxide near break$3 and voltage and probe and 324/765.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:46
L7	2	oxide near break$3 and voltage and probe and 324/761.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:46
L8	5	oxide near break$3 and voltage and probe and 324/757.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:46
L9	0	oxide near break$3 and voltage and probe and 324/756.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:46
L10	11	oxide near break$3 and voltage and probe and 324/754.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:47
L11	0	oxide near break$3 and voltage and probe.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:48
L12	49	oxide near break$3 and voltage and probe	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:48
L13	18	12 and "324"/$.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:48
L14	1739	fritt$3 and voltage	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:48
L15	20	fritt$3 near4 voltage	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:48
L16	9	15 and "324"/$.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:49
L17	2	("5719856" | "6452428").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L18	6	("4055800" | "4112363" | "4362991" | "4767985" | "4845427" | "5033977").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50

L19	43	((probe or pin)) with (tester same (apply$3) near signal)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L20	2	("20040174177").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/18 10:50
L21	2	("5600257" | "6480012").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L22	3	("5418746" | "5842155" | "5883521").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L23	2	("6462572").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/18 10:50
L24	12771	324/765,754-762.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L25	10	("4267538" | "5086271" | "5172051" | "5656979" | "5760599" | "5880540" | "6140885" | "6218910" | "6297659" | "6339338").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L26	254	L24 and power adj supply and probe near4 pin and signals	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L27	7	("4477774" | "4851707" | "5258654" | "5523633" | "5773987" | "5936419" | "6057694").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L28	123	L24 and tester and voltage near4 drivers	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L29	1	((probe or pin)) with (tester same apply$3) near signal	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L30	3	("3159787" | "3982240").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L31	6	("4507576" | "4947113" | "5164663" | "5200696" | "5266894" | "5436559").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L32	5	("4517512" | "4875006" | "5095262" | "5477139" | "5946250").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50

EAST Search History

L33	11	L24 and fritting	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L34	2	("4792932" | "5794175").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L35	942	L24 and power adj supply and probe and signals	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L36	9	("4100532" | "4131848" | "4468614" | "4648104" | "4710704" | "4953095" | "5057774" | "5321354" | "5521524").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L37	92	("20060061374" "5747999" "20050200363" "6777967" "7061259" "20020021142" "20040174177" "20060145716" "20060192578" "4574474" "5428298" "5742173" "6075373" "6130543" "6614250" "6870385" "6933740" "6967498" "20040027142" "20040027143" "20040027146" "20040028893" "20060154500" "5811980" "4342957" "4342958" "4471298" "4507605" "5339031" "5565767" "6220891" "6220891" "6765203" "6853364" "20020140650" "20040246018" "5321584" "5471136" "5736862" "6034533" "6459268" "6724193" "7053644" "20020067179" "20030042906" "20060125502" "4257190" RE31109 "4375672" "4631688").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L38	21	fritting adj phenomenon	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L39	12	("3566263" | "4477774" | "4851707" | "5258654" | "5523633" | "5594349" | "5773987" | "5936419" | "6057694" | "6326792" | "6529011").PN. OR ("7061259").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L40	14	("3931506" | "4117397" | "4296370" | "4466850" | "4697142" | "4851707" | "5285151" | "5432460" | "5682049" | "5793212" | "5959448" | "6028573" | "6377858").PN. OR ("6529011").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L41	11	("4267538" | "5086271" | "5172051" | "5656979" | "5760599" | "5880540" | "6140885" | "6218910" | "6297659" | "6339338").PN. OR ("6788090").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L42	8	("4477774" | "4851707" | "5258654" | "5523633" | "5773987" | "5936419" | "6057694").PN. OR ("6777967").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L43	6926	break near (film or layer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L44	263	L43 and (probe or pins) and voltage and (drivers or comparator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50

EAST Search History

L45	244	L44 and test$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L46	55	L45 and electrodes	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L47	30	voltage same drivers and (probes or pins) and test$3 and electrodes and inspect$3 near signal	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L48	5	L46 and "324"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L49	5	L44 and "324"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L50	6926	break near (film or layer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L51	263	L50 and (probe or pins) and voltage and (drivers or comparator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L52	244	L51 and test$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L53	8	("4477774" | "4851707" | "5258654" | "5523633" | "5773987" | "5936419" | "6057694").PN. OR ("6777967").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L54	55	L52 and electrodes	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L55	5	L54 and "324"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50

EAST Search History

L56	12	("3566263" | "4477774" | "4851707" | "5258654" | "5523633" | "5594349" | "5773987" | "5936419" | "6057694" | "6326792" | "6529011").PN. OR ("7061259").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/18 10:50
L57	25	fritting near8 phenomenon	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L58	5	L55	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50
L59	94	("20060061374" "6777967" "7061259" "20020021142" "20040174177" "20060192578" "5428298" "6130543" "5747999" "20050200363" "5811980" "5565767" "5471136" "5736862" "20020067179" "20060145716" "20070063725" "4574474" "5742173" "6075373" "6614250" "6870385" "6933740" "6967498" "20040027142" "20040027143" "20040027146" "20040028893" "20060154500" "20070007984" "5256975" "5384531" "4328264" "4395677" "6545493" "7154261" "20030062917" "20040036861" "20050116728" "20050253611" "20050278134" "20070007979" "4342957" "4342958" "4471298" "4507605" "5339031" "6220891" "6220891" "6765203").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:50

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	1	probe and tester and drivers and fritting and voltage and signal. clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/18 10:24